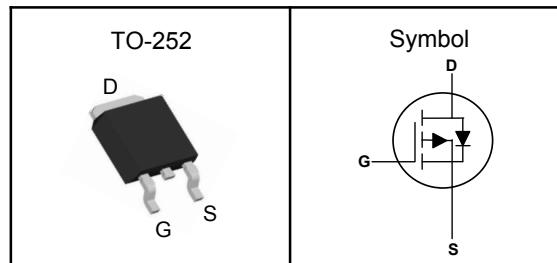


P-Channel Enhancement Mode MOSFET

Features

- Low Rdson for low conduction loss
- Reliable and Rugged
- ROHS Compliant & Halogen-Free

Pin Description



Applications

- Power Management in Desktop Computer
- DC/DC Converters

V _{DSS}	-40	V
R _{DSON-TYP}	10.5	mΩ
I _D	-52	A

Absolute Maximum Ratings (T_C=25°C, Unless Otherwise Noted)

Symbol	Parameter	P-Channel	Unit
V _{DSS}	Drain-Source Voltage	-40	V
V _{GSS}	Gate-Source Voltage	±20	V
T _J	Maximum Junction Temperature	-55 to 150	°C
T _{STG}	Storage Temperature Range	-55 to 150	°C
I _{DM} ^①	Pulse Drain Current Tested	-105	A
I _D	Continuous Drain Current	-52	A
P _D	Maximum Power Dissipation	52.1	W
E _{AS}	Single Pulse Avalanche Energy	146	mJ

Thermal Characteristics

Symbol	Parameter	Rating	Unit
R _{θJA}	Thermal Resistance-Junction to Ambient	62	°C/W
R _{θJC}	Thermal Resistance Junction-Case ₁	2.4	°C/W

Note ① : Max. current is limited by bonding wire.

Note ② : UIS tested and pulse width are limited by maximum junction temperature 150°C.

Note ③ : Surface Mounted on 1in² FR-4 board with 1oz.

P-Channel Enhancement Mode MOSFET

Electrical Characteristics ($T_J=25^\circ\text{C}$, Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
Static Electrical Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_D=-250\mu\text{A}$	-40	---	---	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}}=-32\text{V}$, $V_{\text{GS}}=0\text{V}$	---	---	-1	μA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$, $I_D=-250\mu\text{A}$	-1.0	---	-2.5	V
I_{GSS}	Gate Leakage Current	$V_{\text{GS}}=\pm 20\text{V}$, $V_{\text{DS}}=0\text{V}$	---	---	± 100	nA
$R_{\text{DS(ON)}}$	Drain-Source On-state Resistance	$V_{\text{GS}}=-10\text{V}$, $I_D=-18\text{A}$	---	10.5	13	$\text{m}\Omega$
		$V_{\text{GS}}=-4.5\text{V}$, $I_D=-12\text{A}$	---	15	20	$\text{m}\Omega$
g_{fs}	Forward Transconductance	$V_{\text{DS}}=-5\text{V}$, $I_D=-18\text{A}$	---	24	---	S
Dynamic Characteristics^⑤						
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}$, $V_{\text{DS}}=-15\text{V}$, Freq.=1MHz	---	3500	---	pF
C_{oss}	Output Capacitance		---	323	---	
C_{rss}	Reverse Transfer Capacitance		---	222	---	
$T_{\text{d(on)}}$	Turn-on Delay Time	$V_{\text{DD}}=-15\text{V}$, $V_{\text{GS}}=-10\text{V}$, $R_G=3.3\Omega$, $I_D=-1\text{A}$	---	40	---	nS
T_r	Turn-on Rise Time		---	35.2	---	
$T_{\text{d(off)}}$	Turn-off Delay Time		---	100	---	
T_f	Turn-off Fall Time		---	9.6	---	
Q_g	Total Gate Charge	$V_{\text{DS}}=-20\text{V}$, $V_{\text{GS}}=-4.5\text{V}$, $I_D=-12\text{A}$	---	27.9	---	nC
Q_{gs}	Gate-Source Charge		---	7.7	---	
Q_{gd}	Gate-Drain Charge		---	7.5	---	
Source-Drain Characteristics						
$V_{\text{SD}}^{④}$	Diode Forward Voltage	$V_{\text{GS}}=0\text{V}$, $I_s=-1\text{A}$, $T_J=25^\circ\text{C}$	---	---	-1.0	V

Note ④: Pulse test (pulse width 300us, duty cycle 2%).

Note ⑤ : Guaranteed by design, not subject to production testing.

P-Channel Enhancement Mode MOSFET

Typical Characteristics

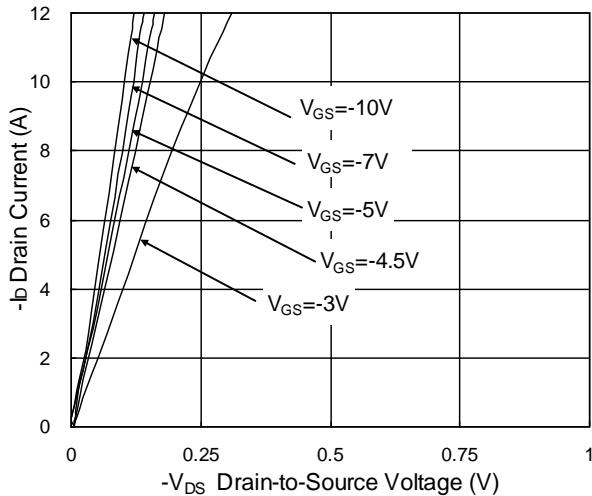


Fig.1 Typical Output Characteristics

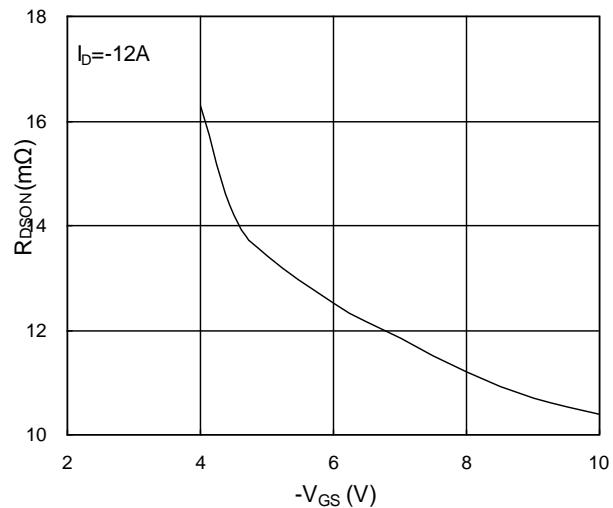


Fig.2 On-Resistance v.s Gate-Source

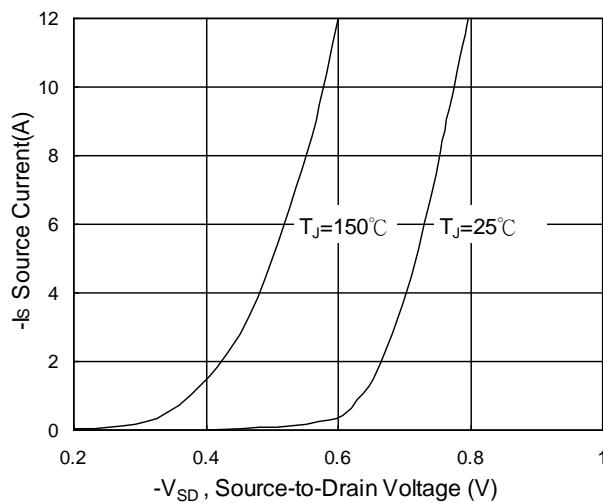


Fig.3 Forward Characteristics Of Reverse

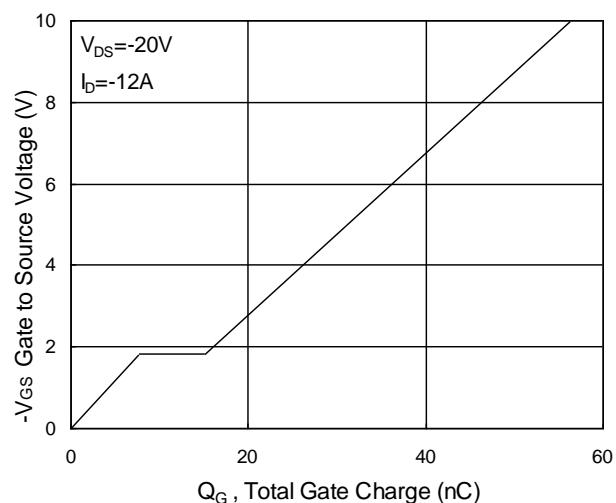


Fig.4 Gate-Charge Characteristics

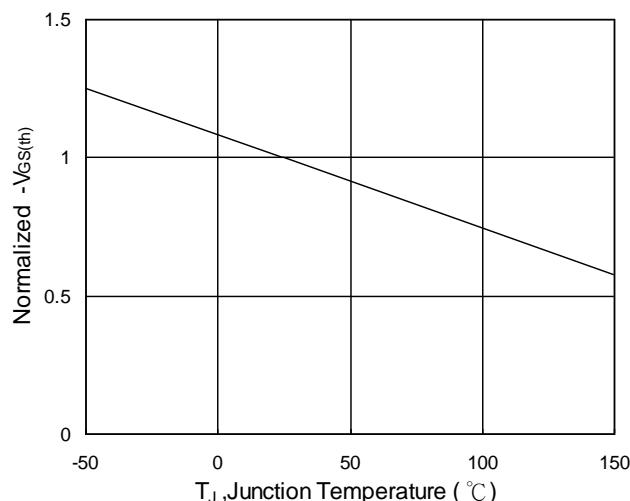


Fig.5 Normalized $V_{GS(th)}$ v.s T_J

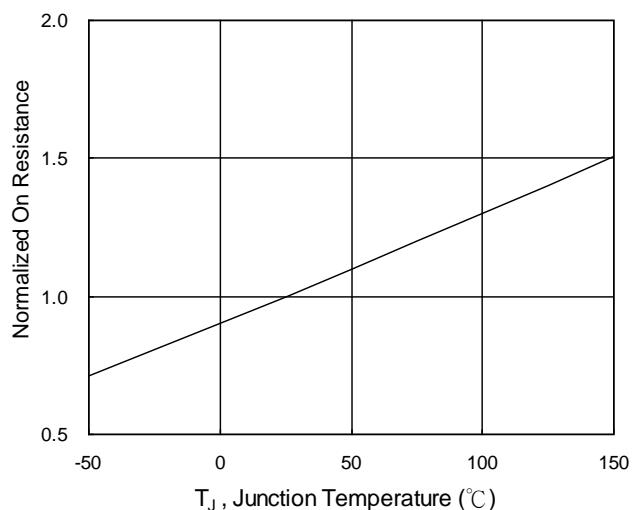
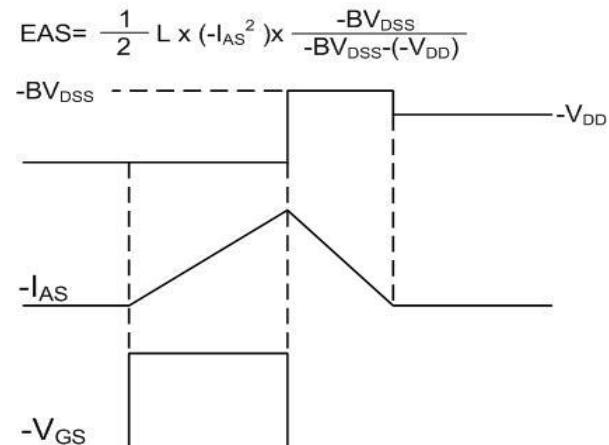
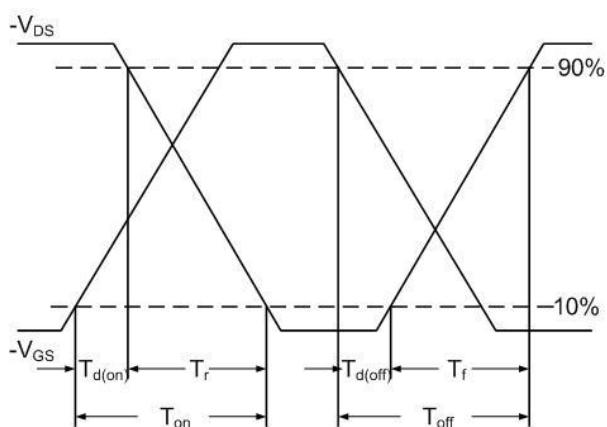
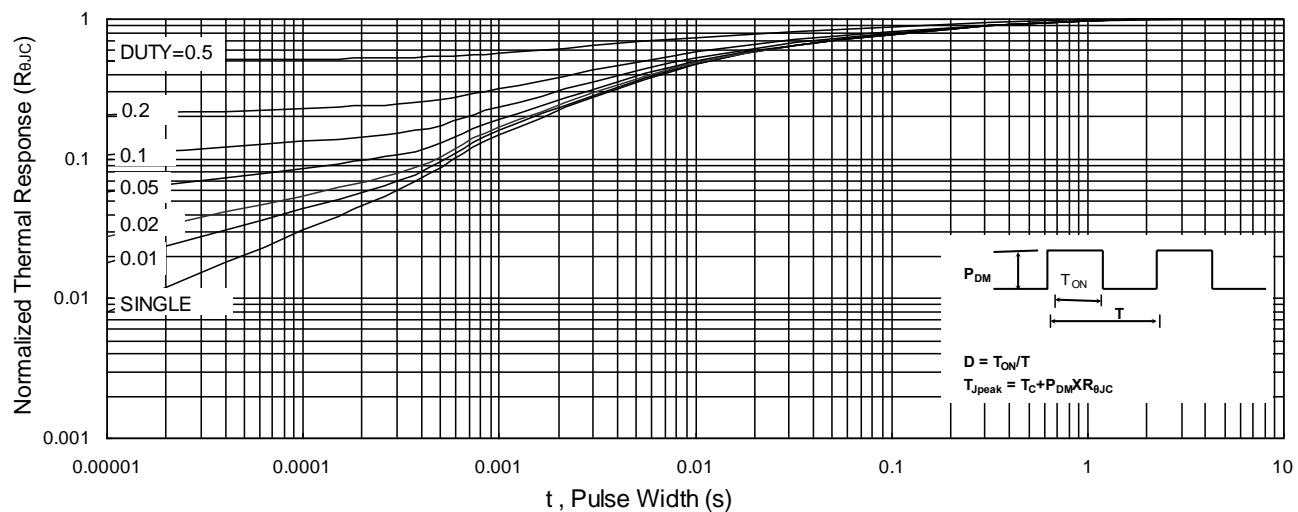
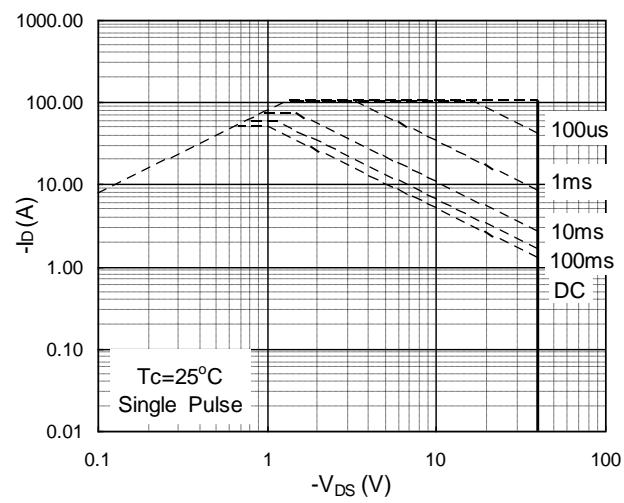
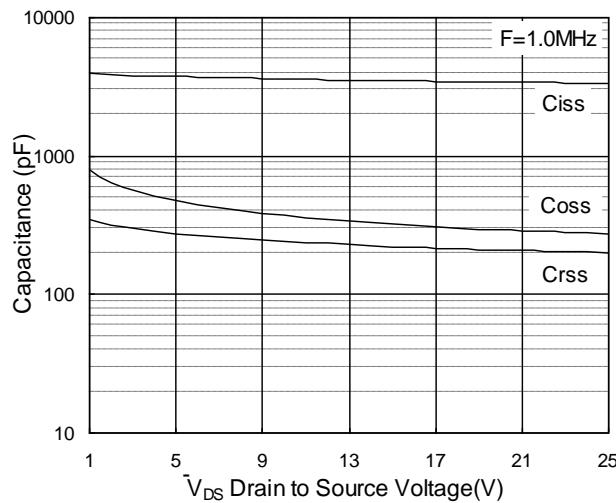


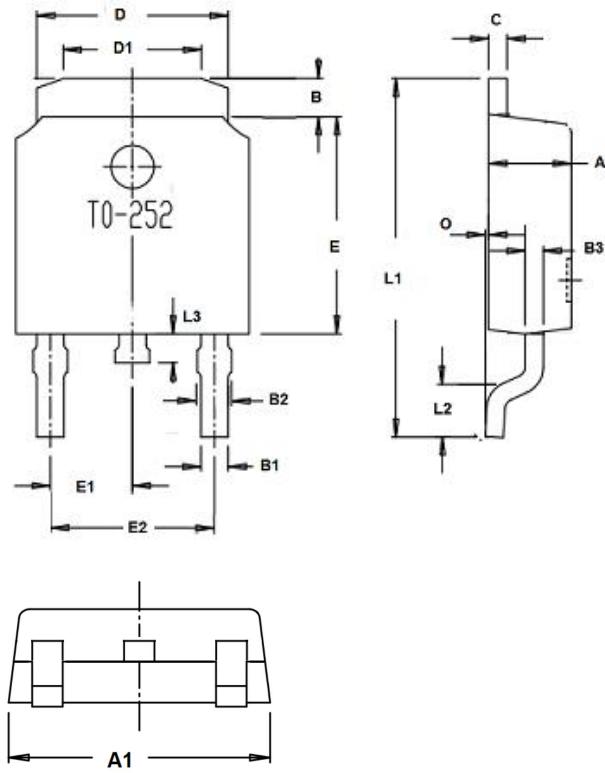
Fig.6 Normalized $R_{DS(on)}$ v.s T_J

P-Channel Enhancement Mode MOSFET



P-Channel Enhancement Mode MOSFET

TO-252 Package Outline Dimensions



Dim.	Min.	Max.
A	2.1	2.5
A1	6.3	6.9
B	0.96	1.42
B1	0.74	0.86
B2	0.74	0.94
C	Typ0.5	
D	5.33	5.53
D1	3.65	4.05
E	6.0	6.2
E1	Typ2.29	
E2	Typ4.58	
O	0	0.15
L1	9.9	10.5
L2	Typ1.65	
L3	0.6	1.0
All Dimensions in millimeter		